Analog CMOS Integrated Circuit Design Cheat Sheet

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Model of MOS Transistors

Process parameters (n, V_{TH}, KP, V_E) :

$$t_{OX} = \frac{L_{min}}{50} \tag{1}$$

$$t_{si} = \sqrt{\frac{2\epsilon_{si}(\Phi - V_{BD})}{qN_B}} \tag{2}$$

$$C_{OX} = \frac{\epsilon_{OX}}{t_{OX}} \tag{3}$$

$$C_D = \frac{\epsilon_{si}}{t_{si}} \tag{4}$$

$$KP = \mu C_{OX} \tag{5}$$

$$\beta = KP\frac{W}{L} \tag{6}$$

$$Q_{dep} = \sqrt{4q\epsilon_{si}|\Phi_F|N_{sub}} \tag{7}$$

$$V_{TH0} = \Phi_{MS} + 2\Phi_F + \frac{Q_{dep}}{C_{OX}} \tag{8}$$

Changing the Gate voltage V_{GS} will thus change the conductivity of the channel and hence the current I_{DS} . In a similar way, changing the Bulk voltage V_{BS} will thus also change the conductivity of the channel and will thus change the current I_{DS} as well. The gate gives the MOST operation, whereas the bulk gives JFET operation.

Indeed, a Junction FET is by definition a FET in which the current is controlled by a junction capacitance.

All MOST devices are thus parallel combinations of MOSTs and JFETs.

The Bulk voltage works like a "back-gate", which is also called as "body effect":

$$V_{TH} = V_{TH0} + \gamma (\sqrt{|2\Phi_F| + V_{BS}} - \sqrt{|2\Phi_F|})$$
(9)

$$n = \frac{\gamma}{\sqrt{|2\Phi_F| + V_{BS}}} = 1 + \frac{C_D}{C_{OX}} \tag{10}$$

In linear region:

$$I_{DS} = \beta [(V_{GS} - V_{TH})V_{DS} - \frac{1}{2}V_{DS}^2]$$
(11)

$$R_{on} = \frac{1}{\beta(V_{GS} - V_{TH})} \tag{12}$$

Channel-Length modulation in saturation region:

$$K' = \frac{KP}{2n} \tag{13}$$

$$\lambda = \frac{1}{V_D L} \tag{14}$$

$$I_{DS} = K' \frac{W}{L} (V_{GS} - V_{TH})^2 (1 + \lambda V_{DS})$$
(15)

$$r_o = \frac{\partial V_{DS}}{\partial I} \approx \frac{1}{V_L} = \frac{V_E L}{I_L}$$
 (16)

Saturation region has three distinctive regions: weak-inversion (exponential region), strong-inversion, and velocity saturation.

Value Examples In $0.35\mu m$ Process Nodes Symbols Values dielectric constant of sub-silicon ϵ_{si} 1 pF/cmdielectric constant of gate-oxide ϵ_{OX} 0.34 pF/cm $1.6 \times 10^{-19} \text{ C}$ electron charge minium channel length $0.35~\mu\mathrm{m}$ width of gate-oxide $0.1~\mathrm{nm}$ width of depletion layer 7 nm0.6 V junction built-in voltage drain-bulk voltage -3.3V $0.5 \ \mu F/cm^2$ gate-oxide capacitance C_{OX} depletion layer capacitance C_D $0.1 \ \mu F/cm^2$ $4 \times 10^{17} \text{ cm}^{-3}$ bulk doping level $250 \text{ cm}^2/\text{Vs}$ P type mobility rate N type mobility rate $600 \text{ cm}^2/\text{Vs}$ N type KP $300 \ \mu A/V^2$ $1.2 \cdots 1.5$ $|2\Phi_F|$ 0.6 V $0.5 \cdots 0.8 \text{ V}^{\frac{1}{2}}$ N type K' $100 \ \mu A/V^2$ P type K' $40 \ \mu A/V^2$ V_{GSTt} 70 mV 10^7 cm/s $0.2 \ \mu \mathrm{m/V}$

Weak-Inversion

$$I_{DS} = I_{D0} \frac{W}{I} e^{\frac{V_{GS}}{R}}$$

$$\tag{17}$$

$$g_m = \frac{\partial I_{DS}}{\partial V_{GS}} = \frac{I_{DS}}{n \frac{KT}{q}} \tag{18}$$

strong-inversion

Ignore channel-length modulation:

$$I_{DS} = K' \frac{W}{L} (V_{GS} - V_{TH})^2 \tag{19}$$

$$g_m = \frac{2I_{DS}}{V_{GS} - V_{TH}} \tag{20}$$

Transition Point Between Weak-Inversion and Strong-Inversion

The voltage and current at transition point between weak-inversion and strong-inversion:

$$V_{GSt} = 2n\frac{KT}{q} + V_{TH} \tag{21}$$

$$I_{DSt} \approx K' \frac{W}{L} (2n \frac{KT}{a})^2 \tag{22}$$

EKV model, a smooth model for weak-inversion and strong-inversion regions:

$$I_{DS} = K' \frac{W}{L} (V_{GS} - V_{TH})^2 [ln(1 + e^{\frac{V_{GS}}{V_{GSt}}})]^2$$
(23)

Let

$$v = \frac{V_{GS}}{V_{GSt}} \tag{24}$$

$$i = \frac{I_{DS}}{I_{DS}} = [ln(1 + e^{v})]^{2}$$
(25)

then.

$$v = \ln(e^{\sqrt{i}} - 1) \tag{26}$$

$$V_{GS} - V_{TH} = V_{GSTt} ln(e^{\sqrt{i}} - 1)$$

$$\tag{27}$$

where:

$$V_{GSTt} = V_{GSt} - V_{TH} = 2n \frac{KT}{q}$$
(28)

When v = 1, i = 1, we also have:

$$I_{DSt} = K' \frac{W}{L} (V_{GSt} - V_{TH})^2$$
 (29)

Velocity Saturation

$$I_{DS} = WC_{OX}v_{sat}(V_{GS} - V_{TH})$$

$$g_m = WC_{OX}v_{sat}$$
(30)

Transition Point Between Strong-Inversion and Velocity Saturation

A smooth model for strong-inversion and velocity saturation regions

$$I_{DS} = \frac{K' \frac{W}{L} (V_{GS} - V_{TH})^2}{1 + \theta (V_{GS} - V_{TH})}$$
(32)

where:

$$\theta = \frac{\mu}{2n} \frac{1}{v_{sat}L} \tag{33}$$

 θL is constant:

$$\theta L = \frac{\mu}{2n} \frac{1}{v_{sat}} \tag{34}$$

$$g_{m,sat} = WC_{OX}v_{sat} = \frac{K'W}{\theta L} \tag{35}$$

The voltage and current at transition point between strong-inversion and velocity saturation: $\frac{1}{2}$

$$V_{GSt} = \frac{1}{\theta} + V_{TH} = 2nL \frac{v_{sat}}{\mu} + V_{TH}$$
 (36)

$$I_{DSt} = K'WL(2n\frac{v_{sat}}{\mu})^2 \tag{37}$$

1st Order Time-constants and Transfer-Constants (TTCs)

 $\overline{\mathbf{A}}$ system with N frequency-dependent elements, th transfer function in complex-frequency form:

$$H_s = \frac{a_0 + a_1 s}{1 + b_1 s} \tag{38}$$

where:

$$a_0 = H^0 (39)$$

$$b_1 = \sum_{i=1}^{N} \tau_i^0 \tag{40}$$

$$a_1 = \sum_{i=1}^{N} \tau_i^0 H^i \tag{41}$$

where H^0 is the low-frequency gain:

$$H^0: C_1, C_2, \cdots, C_N = 0 (42)$$

or:

$$H^0: L_1, L_2, \cdots, L_N = 0 (43)$$

For capacitor:

$$\tau_i^0 = C_i R_i^0 \tag{44}$$

or for inductor:

$$\tau_i^0 = \frac{L_i}{R^0} \tag{45}$$

(46)

where R_i^0 is the resistance seen by the capacitor C_i looking into port i with all other reactive elements connected to the other ports at their zero value (hence the superscript), namely open-circuited capacitors (and short circuited inductors):

$$R_i^0: C_1, C_2, C_{i-1}, C_{i+1}, \cdots, C_N = 0$$

or:

$$R_i^0: L_1, L_2, \cdots, L_{i-1}, L_{i+1}, \cdots, L_N = 0$$
 (47)

Bandwidth estimation by 1st-order TTCs:

$$\omega_h \approx \frac{1}{b_1 - \frac{a_1}{a_0}} = \frac{1}{\sum_{i=1}^N \tau_i^0 (1 - \frac{H^i}{H^0})}$$
(48)

2nd Order Time-constants and Transfer-Constants (TTCs)

A system with 2 frequency-dependent elements, th transfer function:

$$H_s = \frac{a_0 + a_1 s + a_2 s^2}{1 + b_1 s + b_2 s^2} \tag{49}$$

where:

$$a_0 = H^0 (50)$$

$$b_1 = \tau_1^0 + \tau_2^0 \tag{51}$$

$$a_1 = \tau_1^0 H^1 + \tau_2^0 H^2 \tag{52}$$

$$b_2 = \tau_1^0 \tau_2^1 = \tau_2^0 \tau_1^2 \tag{53}$$

$$a_2 = \tau_1^0 \tau_2^1 H^{12} = \tau_2^0 \tau_1^2 H^{12} \tag{54}$$

in which, H^1 (H^2) evaluated with the frequency-dependent element at the port 1(2) at its infinite value (i.e., shorted capacitors and open inductors):

$$H^1: C_1 = \infty, C_2 = 0 (55)$$

$$H^2: C_1 = 0, C_2 = \infty (56)$$

or:

$$H^1: L_1 = \infty, L_2 = 0 (57)$$

$$H^2: L_1 = 0, L_2 = \infty (58)$$

For capacitor:

$$\tau_1^0 = C_1 R_1^0 \tag{59}$$

$$\tau_2^0 = C_2 R_2^0 \tag{60}$$

$$\tau_1^2 = C_1 R_1^2 \tag{61}$$

$$\tau_2^1 = C_2 R_2^1 \tag{62}$$

or for inductor:

$$\tau_1^0 = \frac{L_1}{R_2^0} \tag{63}$$

$$\tau_2^0 = \frac{L_2}{R_2^0} \tag{64}$$

$$\tau_1^2 = \frac{L_1}{R_1^2} \tag{65}$$

$$\tau_2^1 = \frac{L_2}{R^1} \tag{66}$$

in which, R_1^2 is the resistance seen by C_1 (the subscript) when C_2 (the superscript) is infinite valued (shorted):

$$R_1^2: C_2 = \infty \tag{67}$$

$$R_2^1: C_1 = \infty (68)$$

or:

$$R_1^2: L_2 = \infty \tag{69}$$

$$R_2^1: L_1 = \infty \tag{70}$$

General Time-constants and Transfer-Constants (TTCs)

A system with N frequency-dependent elements, th transfer function:

$$H_s = \frac{a_0 + a_1 s + a_2 s^2 \dots + a_n s^n + \dots}{1 + b_1 s + b_2 s^2 \dots + b_n s^n + \dots}$$
(71)

where:

$$a_0 = H^0 \tag{72}$$

$$b_1 = \sum_{i=1}^{N} \tau_i^0 \tag{73}$$

$$a_1 = \sum_{i=1}^{N} \tau_i^0 H^i \tag{74}$$

$$b_2 = \sum_{i=1}^{i < j} \sum_{j=i+1}^{j \le N} \tau_i^0 \tau_j^i$$

$$i < j \quad j \le N$$

$$(75)$$

$$a_2 = \sum_{i=1}^{i < j} \sum_{j=i+1}^{j \le N} \tau_i^0 \tau_j^i H^{ij}$$
 (76)

$$b_n = \sum_{i=1}^{i < j} \sum_{j=i+1}^{j < k} \sum_{k=j+1\dots}^{k < \dots \le N} \tau_i^0 \tau_j^i \tau_k^{ij} \dots$$
 (77)

$$a_n = \sum_{i=1}^{i < j} \sum_{j=i+1}^{j < k} \sum_{k=j+1\cdots}^{k < \dots \le N} \tau_i^0 \tau_j^i \tau_k^{ij} \cdots H^{ijk\cdots}$$
(78)

and for capacitor:

$$\tau_i^0 = C_i R_i^0 \tag{79}$$

$$f^{k\cdots} = C_i R_i^{jk\cdots} \tag{80}$$

or for inductor:

$$\tau_i^0 = \frac{L_i}{R^0} \tag{81}$$

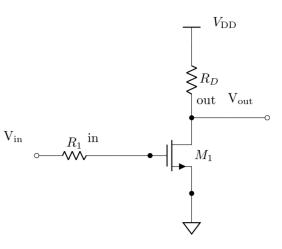
$$\tau_i^{jk\cdots} = \frac{L_i}{R_i^{jk\cdots}} \tag{82}$$

In the form of zeros and poles:

$$H_s = a_0 \frac{\left(1 - \frac{s}{z_1}\right)\left(1 - \frac{s}{z_1}\right) \cdots \left(1 - \frac{s}{z_m}\right)}{\left(1 - \frac{s}{p_1}\right)\left(1 - \frac{s}{p_1}\right) \cdots \left(1 - \frac{s}{p_n}\right)}$$
(83)

Single Stage Amplifier: Common Source (CS), with Resistive Load

Common Source, with resistance R_D :



Transfer function of voltage gain in low-frequency:

$$A_v^0 = \frac{V_{out}}{V_{in}} = -g_m R_D \tag{84}$$

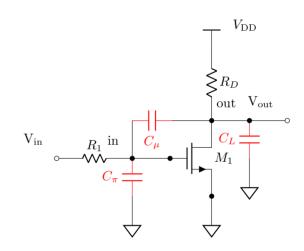
consider channel-length modulation:

$$A_v^0 = \frac{V_{out}}{V_{in}} = -g_m R_D || r_o = -g_m \frac{R_D r_o}{R_D + r_o}$$
(85)

The equivalent resistance at point out look down M1:

$$R_{out} = r_o (86)$$

Consider high-frequency gain with 3 capacitors c_{π}, c_{μ}, c_L :



$$\tau_{\pi}^0 = C_{\pi} R_1 \tag{87}$$

$$\tau_{\mu}^{0} = C_{\mu}(R_{left} + R_{right} + G_{m}R_{left}R_{right}) = C_{\mu}(R_{1} + R_{D} + g_{m}R_{1}R_{D})$$
 (88)

$$\tau_L^0 = C_L R_D \tag{89}$$

$$\tau_{\mu}^{\pi} = C_{\mu} R_D \tag{90}$$

$$\tau_{\pi}^{L} = C_{\pi} R_1 \tag{91}$$

$$\tau_{\mu}^{L} = C_{\mu} R_{1} \tag{92}$$

$$\tau_{\mu}^{\pi L} = \tau_{L}^{\pi \mu} = 0 \tag{93}$$

$$H^{\pi} = H^L = 0 \tag{94}$$

$$H^{\mu} = \frac{r_m || R_D}{R_1 + r_m || R_D} = \frac{R_D}{R_1 + R_D + g_m R_1 R_D}$$
(95)

$$H^{\pi\mu} = H^{L\mu} = H^{L\pi} = 0 \tag{96}$$

$$a_0 = A_v^0 (97)$$

$$b_1 = \tau_{\pi}^0 + \tau_{\mu}^0 + \tau_{L}^0 = R_1[C_{\pi} + C_{\mu}(1 + g_m R_D)] + R_D(C_{\mu} + C_L)$$
(9)

$$a_1 = \tau_{\pi}^0 H^{\pi} + \tau_{\mu}^0 H^{\mu} + \tau_{L}^0 H^L = C_{\mu} R_D \tag{99}$$

$$b_2 = \tau_{\pi}^0 \tau_{\mu}^{\pi} + \tau_{L}^0 \tau_{\mu}^L + \tau_{L}^0 \tau_{\pi}^L = R_1 R_D (C_{\mu} C_{\pi} + C_{\mu} C_L + C_{\pi} C_L) = R_{left} R_{right} (\Delta C)^2$$
 (100)

$$a_2 = \tau_{\pi}^0 \tau_{\mu}^{\pi} H^{\pi\mu} + \tau_L^0 \tau_{\mu}^L H^{L\mu} + \tau_L^0 \tau_{\pi}^L H^{L\pi} = 0$$
(101)

$$b_3 = \tau_{\pi}^0 \tau_{\mu}^{\pi} \tau_{L}^{\pi \mu} = 0$$

$$a_3 = \tau_{\pi}^0 \tau_{\mu}^{\pi} \tau_{L}^{\pi \mu} H^{\pi \mu L} = 0$$
(102)

(103)

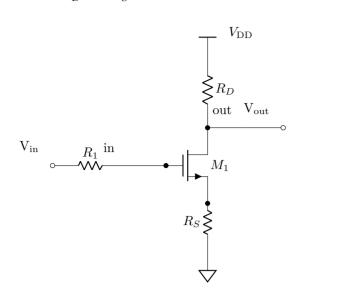
Finally, we have:

$$A_v(s) = \frac{A_v^0(1 - r_m C_\mu s)}{1 + [R_1[C_\pi + C_\mu(1 + g_m R_D)] + R_D(C_\mu + C_L)]s + R_1 R_D(C_\mu C_\pi + C_\mu C_L + C_\pi C_L)s^2}$$
(104)

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Single Stage Amplifier: Common Source (CS), with Source Degeneration

Common Source, with resistance R_D and R_S :



The low frequency gain:

$$A_v^0 = -\frac{g_m R_D}{1 + g_m R_S} \tag{105}$$

The equivalent transconductance:

$$G_m = \frac{g_m}{1 + g_m R_G} \tag{106}$$

consider channel-length modulation and body effect:

$$G_m = \frac{g_m r_o}{R_S + [1 + (g_m + g_{mb})R_s]r_o}$$
 (107)

$$R_{out} = r_o + [1 + (g_m + g_{mb})r_o]R_S \approx g_m r_o R_S$$
 (108)

$$R_{out} = r_o + [1 + (g_m + g_{mb})r_o]R_S \approx g_m r_o R_S$$

$$A_v^0 = -G_m(R_{out}||R_D) = -\frac{g_m r_o}{R_S + [1 + (g_m + g_{mb})R_s]r_o} \{ [r_o + [1 + (g_m + g_{mb})r_o]R_S] ||R_D\}$$
(108)

Single Stage Amplifier: Common Drain (CD) or Source Follower